

Material Issues in Thermal Management of RF Power Electronics

James S. Wilson

Principal Mechanical Engineer

Donald C. Price

Principal Fellow

Raytheon Electronic Systems

Dallas, Texas

Thermal Materials Workshop 2001

Moller Centre, Churchill College

Cambridge University

May 30 - June 1, 2001

James Wilson
972-344-3815
jsw@raytheon.com

Donald Price
972-575-6195
dprice@raytheon.com

REPORT DOCUMENTATION PAGE

Form Approved OMB No.
0704-0188

Public reporting burden for this collection of information is estimated to average 1 hour per response, including the time for reviewing instructions, searching existing data sources, gathering and maintaining the data needed, and completing and reviewing this collection of information. Send comments regarding this burden estimate or any other aspect of this collection of information, including suggestions for reducing this burden to Department of Defense, Washington Headquarters Services, Directorate for Information Operations and Reports (0704-0188), 1215 Jefferson Davis Highway, Suite 1204, Arlington, VA 22202-4302. Respondents should be aware that notwithstanding any other provision of law, no person shall be subject to any penalty for failing to comply with a collection of information if it does not display a currently valid OMB control number. PLEASE DO NOT RETURN YOUR FORM TO THE ABOVE ADDRESS.

1. REPORT DATE (DD-MM-YYYY) 30-05-2001		2. REPORT TYPE Workshop Presentations		3. DATES COVERED (FROM - TO) 30-05-2001 to 01-06-2001	
4. TITLE AND SUBTITLE Material Issues in Thermal Management of RF Power Electronics Unclassified			5a. CONTRACT NUMBER		
			5b. GRANT NUMBER		
			5c. PROGRAM ELEMENT NUMBER		
6. AUTHOR(S) Wilson, James S. ; Price, Donald C. ;			5d. PROJECT NUMBER		
			5e. TASK NUMBER		
			5f. WORK UNIT NUMBER		
7. PERFORMING ORGANIZATION NAME AND ADDRESS Raytheon Electronic Systems Dallas, TXxxxxx			8. PERFORMING ORGANIZATION REPORT NUMBER		
9. SPONSORING/MONITORING AGENCY NAME AND ADDRESS Office of Naval Research International Field Office Office of Naval Research Washington, DCxxxxx			10. SPONSOR/MONITOR'S ACRONYM(S)		
			11. SPONSOR/MONITOR'S REPORT NUMBER(S)		
12. DISTRIBUTION/AVAILABILITY STATEMENT APUBLIC RELEASE					
13. SUPPLEMENTARY NOTES See Also ADM001348, Thermal Materials Workshop 2001, held in Cambridge, UK on May 30-June 1, 2001. Additional papers can be downloaded from: http://www-mech.eng.cam.ac.uk/onr/					
14. ABSTRACT ? System Level ? Description of system(s) ? Thermal management issues ? Temperature gradients ? Absolute temperature levels ? Special array-level (AESAs) problems ? Role of materials at the system level ? Component Level ? Primary source of thermal dissipation ? Unique thermal analysis aspects of RF components ? Role of materials at the component level					
15. SUBJECT TERMS					
16. SECURITY CLASSIFICATION OF:		17. LIMITATION OF ABSTRACT Public Release	18. NUMBER OF PAGES 31	19. NAME OF RESPONSIBLE PERSON Fenster, Lynn lfenster@dtic.mil	
a. REPORT Unclassified	b. ABSTRACT Unclassified	c. THIS PAGE Unclassified	19b. TELEPHONE NUMBER International Area Code Area Code Telephone Number 703767-9007 DSN 427-9007		
					Standard Form 298 (Rev. 8-98) Prescribed by ANSI Std Z39.18

- System Level
 - Description of system(s)
 - Thermal management issues
 - Temperature gradients
 - Absolute temperature levels
 - Special array-level (AESAs) problems
 - Role of materials at the system level
- Component Level
 - Primary source of thermal dissipation
 - Unique thermal analysis aspects of RF components
 - Role of materials at the component level

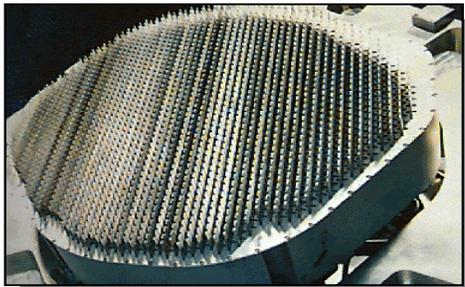
Phased Array System Hierarchy

Phased array hierarchy	Physical dimensions, characteristics	Material issues	Thermal management issues
Active antenna	Meters, many elements	Structural support Thermal gradient	Coolant routing Heat absorption
Slat, Subpanel	Meter several elements	Interconnect, CTE, thermal	Packaging density
RF Module	Collection of MMICs and ICs	Dielectric, CTE, thermal, hermetic	Module attach thermal interface
Device	Power Amplifiers sub- micron active area	Semiconductor Thermal interfaces	Die attach FET layout

Typical RF Platforms / Systems

Airborne and Ground Systems

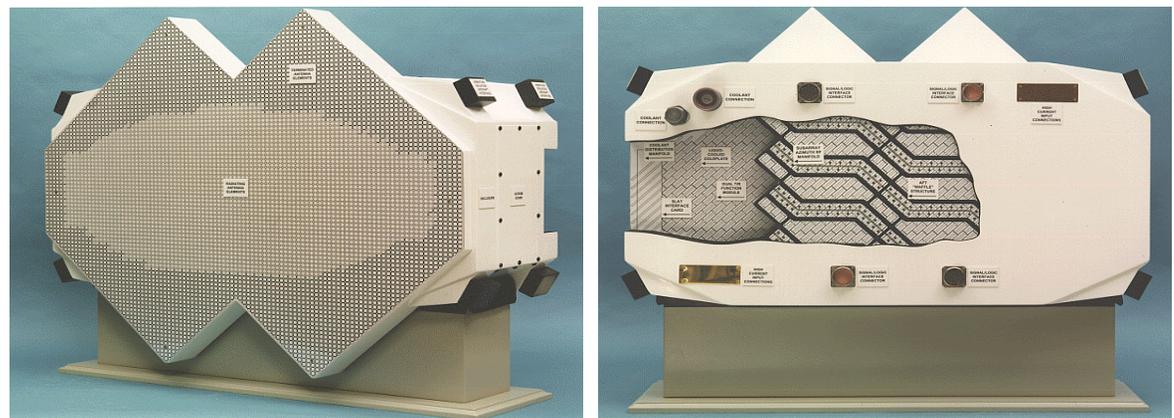
- Often require designs for continuous operation



Airborne



Ground based

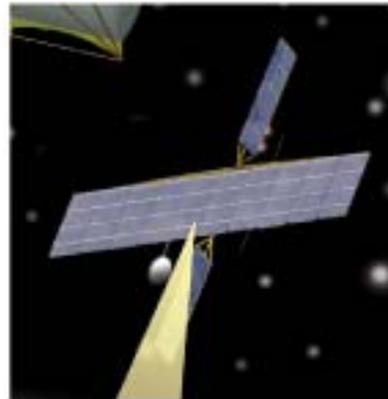
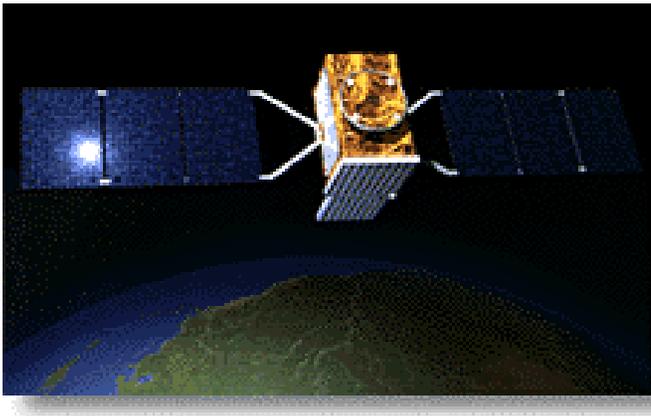


Shipborne

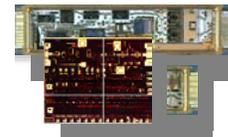
Typical RF Platforms / Systems

Satellite Systems

- Large antenna dimensions
- May have thousands of modules
- May have option of intermittent or short term operation



Modules



MMICs

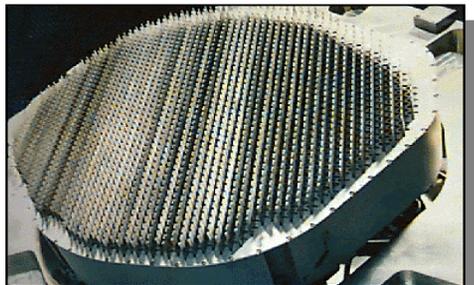


Power Converter

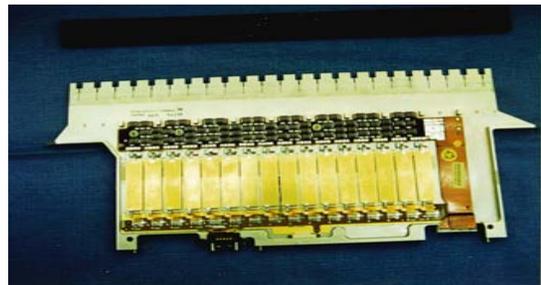
Typical RF Platforms / Systems

Phased-Array Radars

- Phased-array radars typically operate at frequencies from 1 to 30 GHz and dissipate from hundreds to tens of thousands of KW of waste heat
- Phased-array radars often contain many thousands of microwave modules as building blocks for AESA (**Active Electronically Steered Arrays**)
- Power dissipations of ground-based systems are typically higher than airborne systems because of physical size, but dissipation flux levels are comparable



Active Array



Subarray (Slat)

Modules



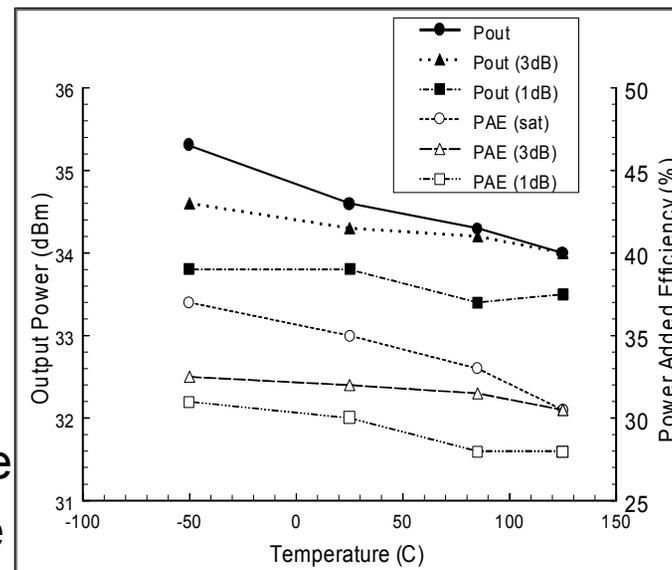
MMICs



Power Converter

Critical Thermal Management Issues Related to Cold Plate Design

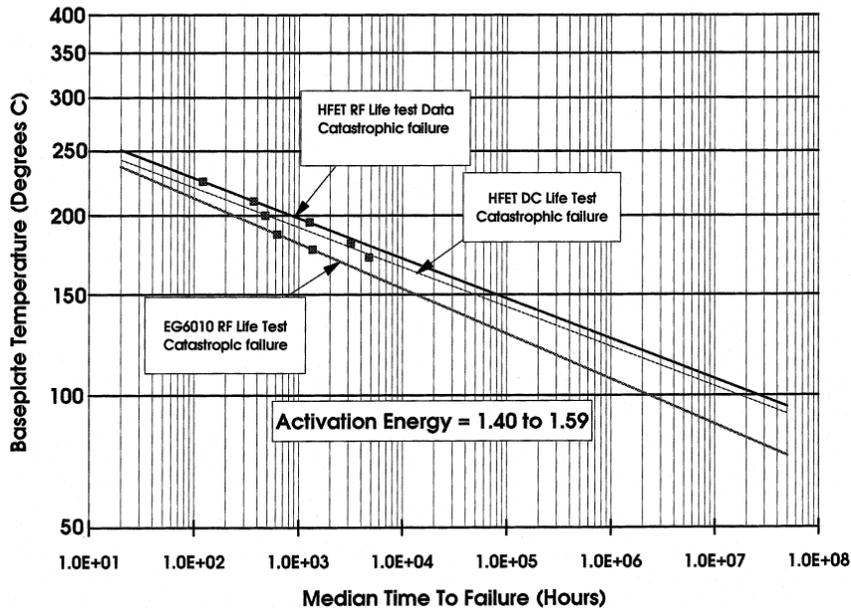
- Temperature Issues
 - Absolute temperature
 - Reliability
 - Electrical performance
 - Failure temperature limit
 - Temperature gradients
 - RF phase shift is temperature dependent
 - Higher operating frequencies are more demanding
 - Gradients need to be constant over operating frequency range from a calibration standpoint



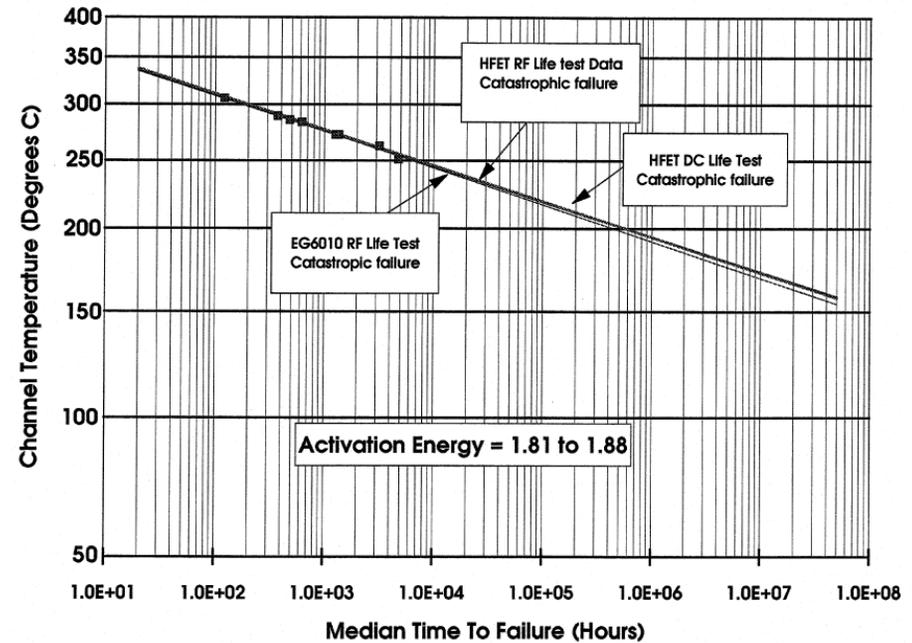
Operating Frequency of Phased-Array (GHz)	Maximum Allowable Temperature Difference Across Array (°C)
5	20
10	10
20	5
40	2.5
80	1.3

Reliability Issue Requires Use of Channel Temperature

ARRHENIUS PLOT



ARRHENIUS PLOT



Same data plotted considering either base or channel temperature

Role of Materials

System Level

- System usually employs cold plate structures which become the heat sink for the dissipating electronics
- Cold plate cooling methods
 - Forced fluid
 - Phase change material (both cyclical and expendable)
 - Heat pipes and capillary pump loops
- Thermal conductivity enhancements for cold plates in use
 - High conductivity graphite (TPG) for lateral conduction
 - Convection enhancement with compact finstock and aluminum foams
 - Phase change material conductivity enhancement with high thermal conductivity graphite foam (satellite and missile applications)

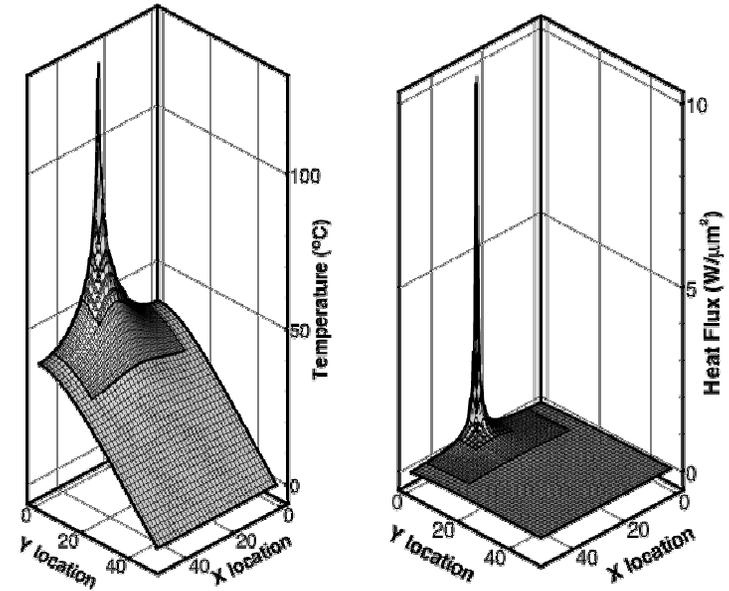
Role of Materials

System Level (continued)

- Wide environmental operating range requires that coefficient of thermal expansion (CTE) differences be addressed
 - RF electronic package materials are set and not likely to change
 - Constrain the cold plates
 - Aluminum Silicon Carbide cold plates provide good match
 - Compliant bonds
 - Thermal concerns (this is often the weak link in the thermal design)
 - Good for repairability concerns
- Material compatibility (from the standpoint of galvanic corrosion) must also be considered
 - Long shelf life required
 - Usually solved by metal plating

Power Dissipation and Heat Flux Issues

	Typical Dissipation (Watts)	Typical Heat Flux (W/cm ²)
FET	1 to 15	Order of 1E7 at junction
MMIC Several FETs	1 to 20	100 - 2000 (at base MMIC)
Module (several MMICs)	1 to 50	1 to 5
Coldplate (several modules)	10 to 2000	0.5 to 3
System (several coldplates)	100 to many kW	Order of 1



Concentrated heat flux
at device junction

Outline

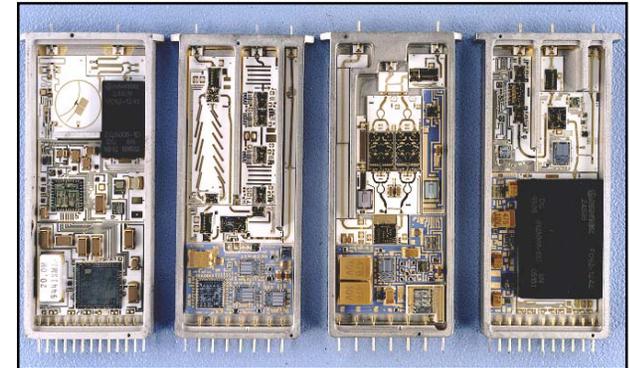
TR Module and MMIC Thermal Issues

- TR Module and MMICs
 - Description
 - Materials
 - Analysis
 - Specialized techniques
 - Examples
 - Verification
 - IR imaging

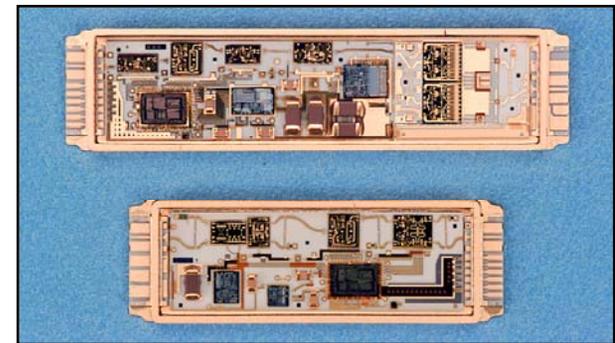
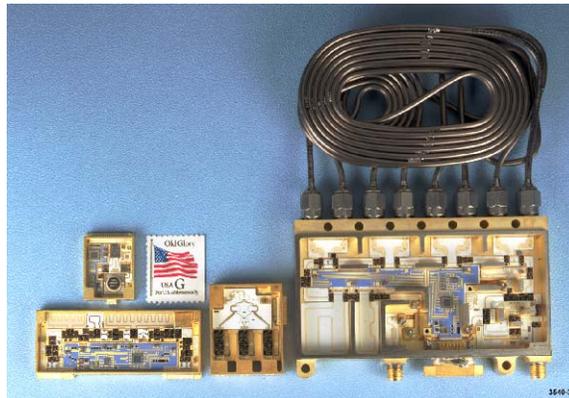
Illustration of TR Modules

- TR modules are the basic building blocks of phased- array antennas
- Typically a single T/R channel

Towed Decoy



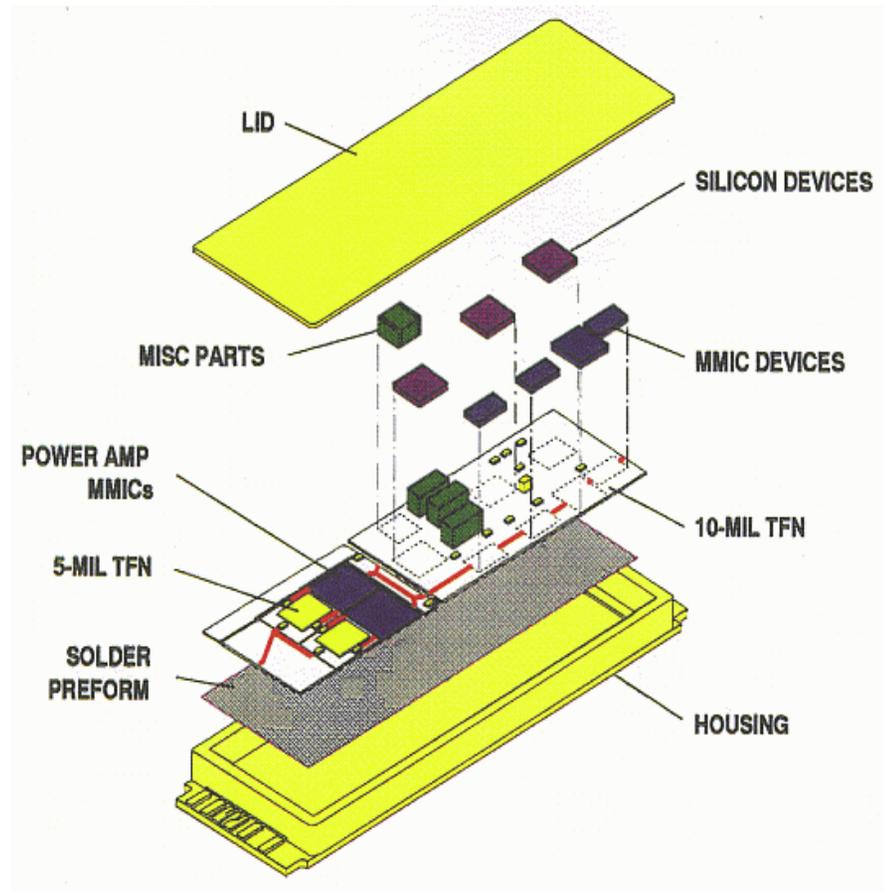
Space



Airborne Radar

Packaging of TR Modules

- Typically require hermetic sealing
 - Welded and brazed connections
- Built-in layers
 - Thermal interfaces are important for power devices
 - Require CTE matched materials



Role of Materials

Package Level

- Dielectric substrates
 - Al_2O_3 , BeO, AlN, thick film, some circuit board
- Heat spreaders for MMICs/Module base
 - Copper Moly, Copper Tungsten, Diamond, Molybdenum, Kovar, Titanium
- Die attach
 - Solders (AuSn, SnPb, Indium)
 - Silver-filled epoxy
 - Z-axis material and solders for flip chip
- Module attach
 - Compliant adhesives, filled epoxies, metal-metal
 - Ball grid array

Module/MMIC Thermal Analysis

Requirements for Numerical Solution

- Numerically difficult
 - Large scale range
 - Non-linear material properties (GaAs, GaN, SiC, BeO)
 - Fully three-dimensional
 - Pulsed operation (transient analysis required)
- Often a majority of the total temperature rise from the junction to sink is in the module and MMIC
 - Thermal design of module/MMIC most important from an ambient-to-junction temperature rise perspective

Transition From System To Device

Antenna Level

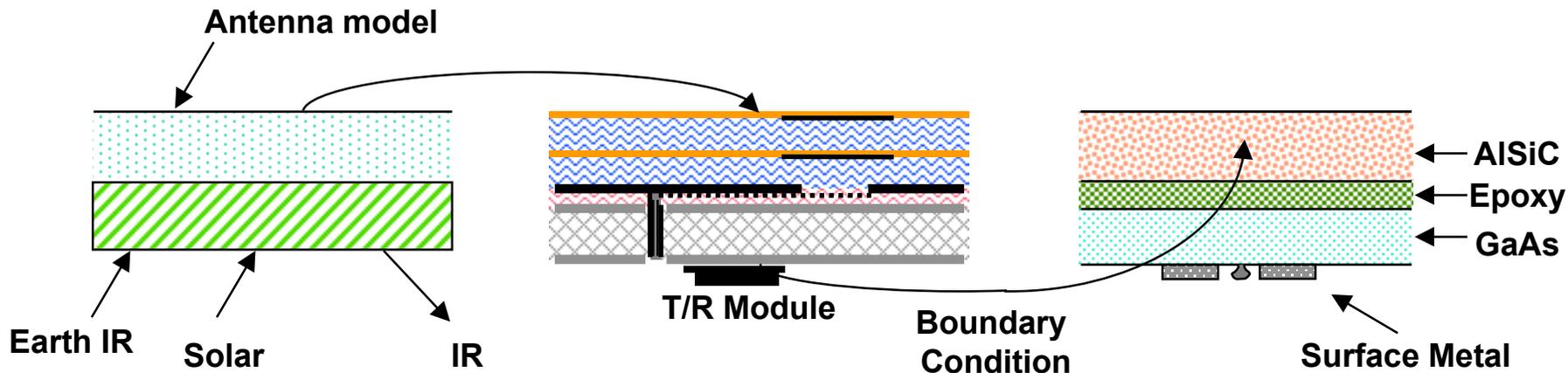
- Orbit environment or system level analysis
- Provide boundary condition for module model
- Time scale in minutes

Module Level

- Boundary condition from antenna model
- Predict module base temperature for operating conditions
- Time scale in seconds

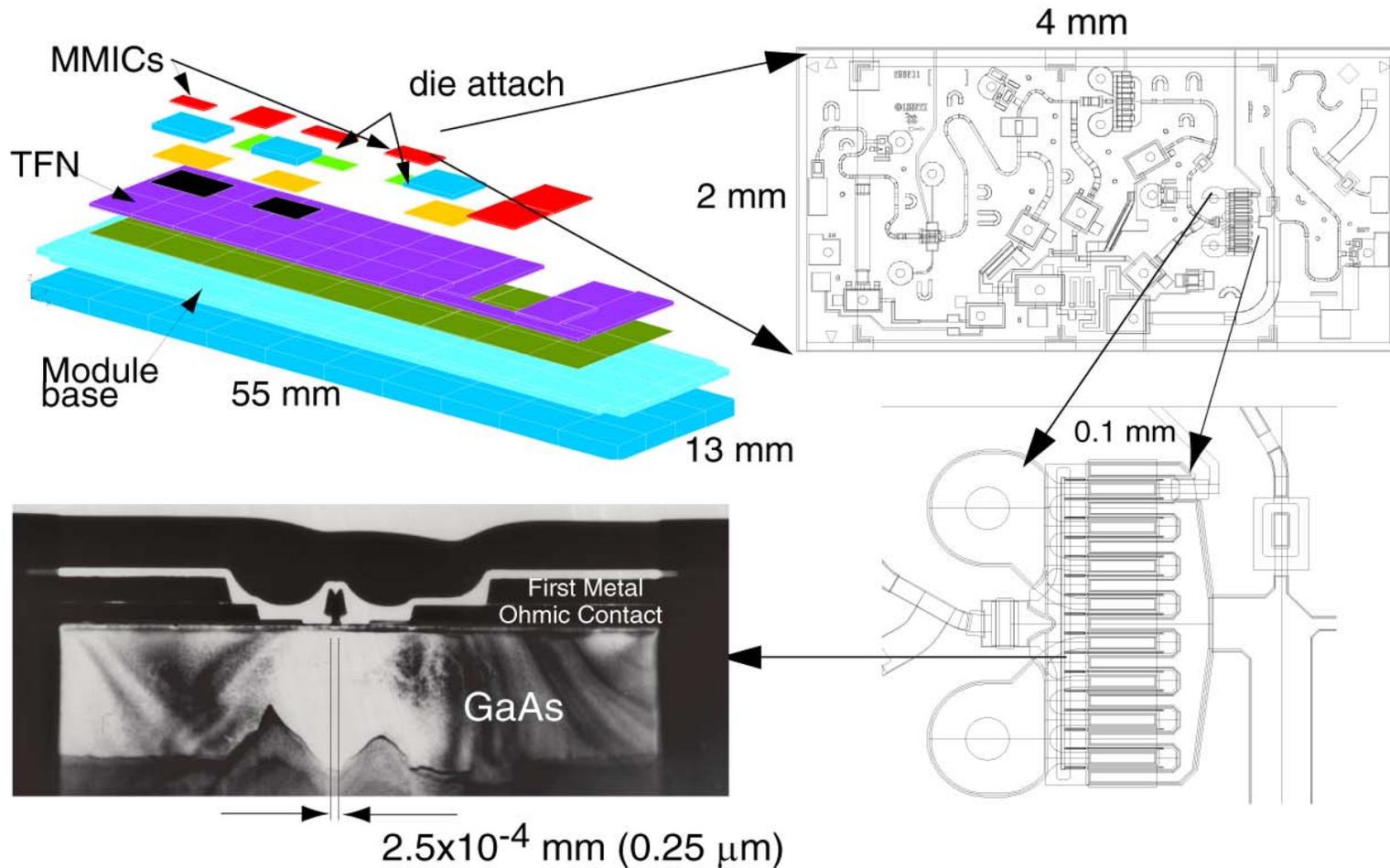
MMIC Level

- Boundary condition from module model
- Junction temperature prediction
- Time scale in microseconds



Scale Variation

MMICs and Microwave Modules



5 to 7 orders of magnitude variation in both space and time scales

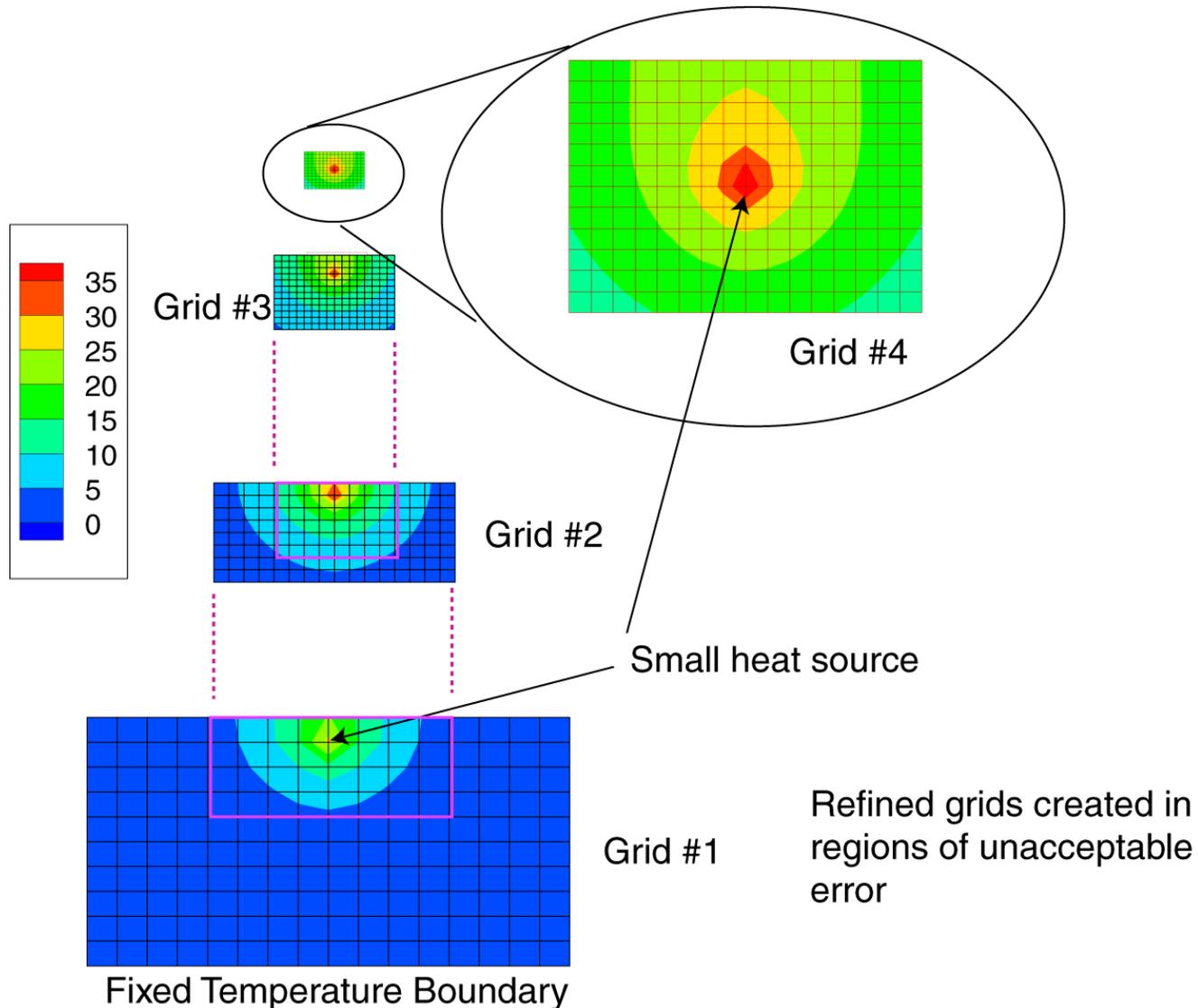
Power Amplifiers

Often Critical Component

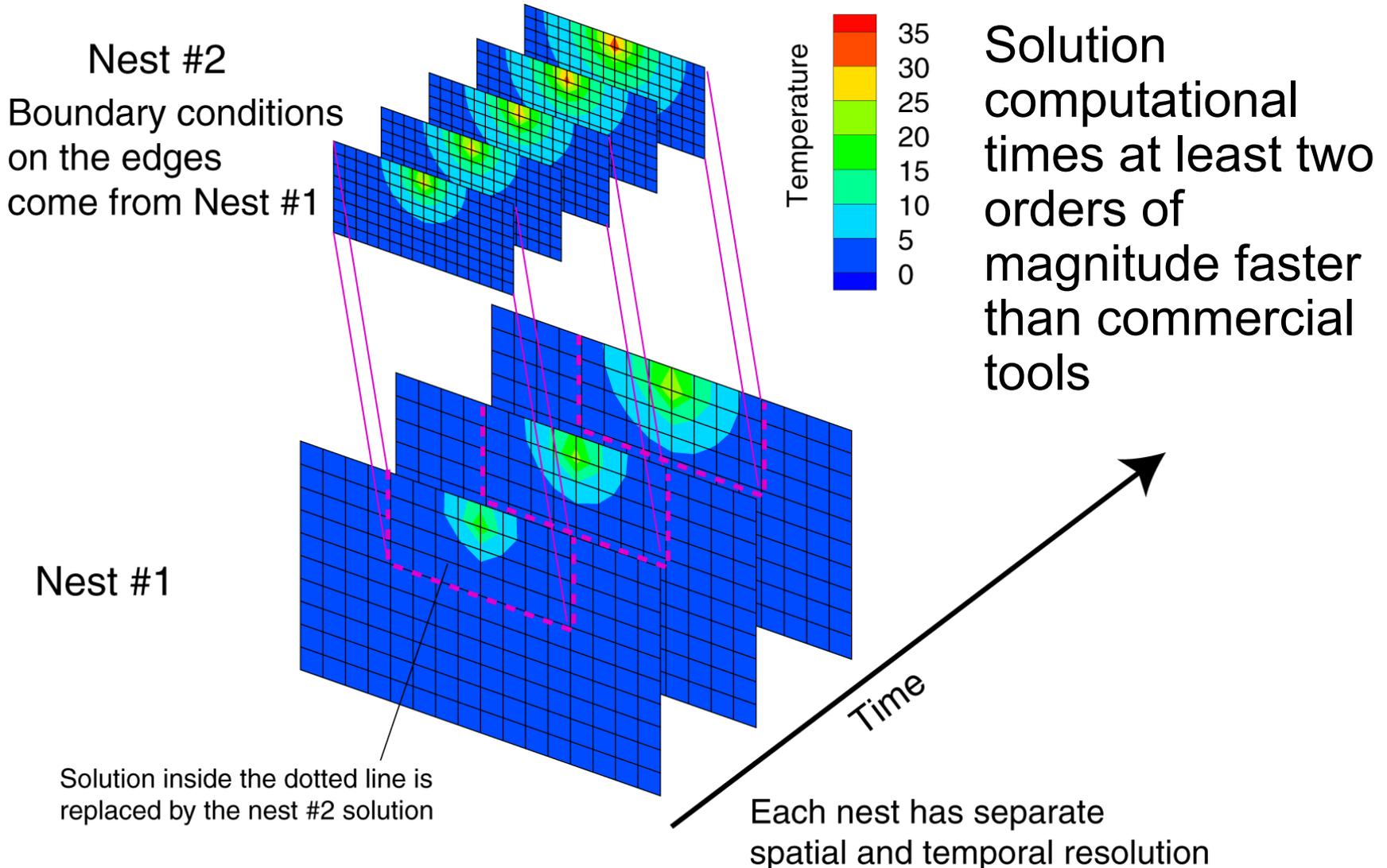
- RF Power Amplifiers
 - GaAs dissipation on the order of 1 W/mm
 - GaN currently at 5 W/mm, soon to be near 9 W/mm with process improvements
 - GaAs heat flux on the order of 1000 W/cm² at base of amplifier (several thousand for GaN/SiC)
 - Often operated in a pulsed mode
 - Duty-cycle (time-average) power will usually apply below MMIC base (assuming pulse width less than 1 msec)

- Large scale range(s) require specialized approach for solving FET/MMIC time dependent thermal problems
 - Finite Difference Approximations
 - Uniform Grid Spacing
 - Control Volume Formulation
 - Effective thermal properties smeared across multiple materials
 - Arbitrary alignment between grid and physical geometry
 - Successive Refinement in space and time
 - Like graphics information transfer on internet

Steady-State Nesting

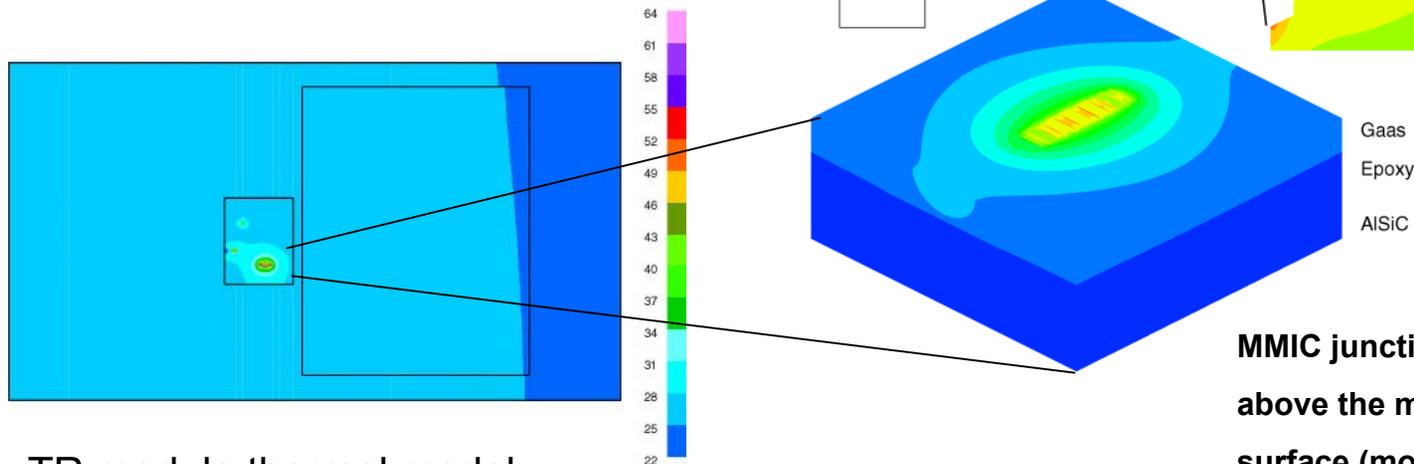
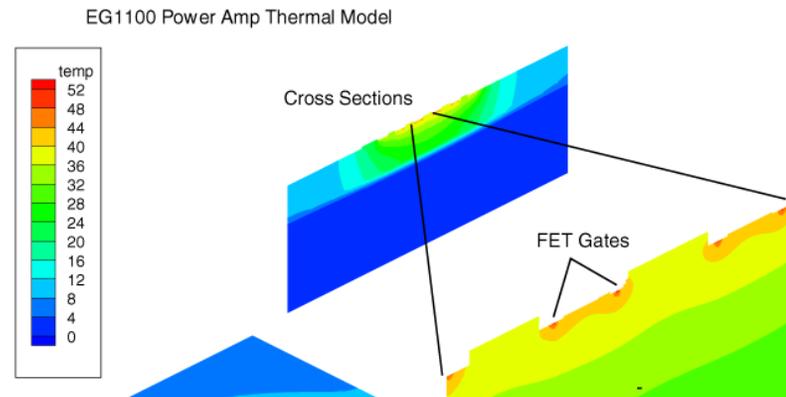
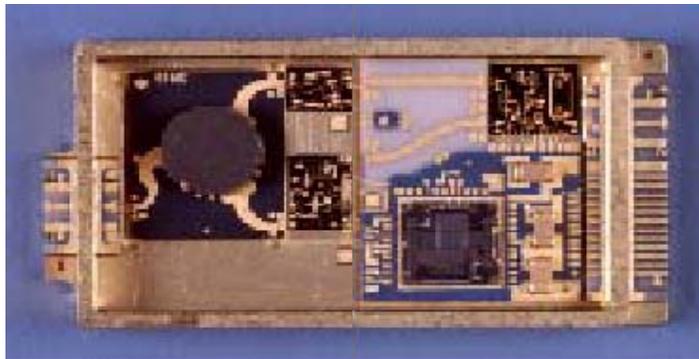


Transient Nesting



Example TR Module/MMIC Model Results

Significant portion of the rise in the GaAs
Future module packaging techniques (flip chip, BGA) still are on the order of 60 C rise



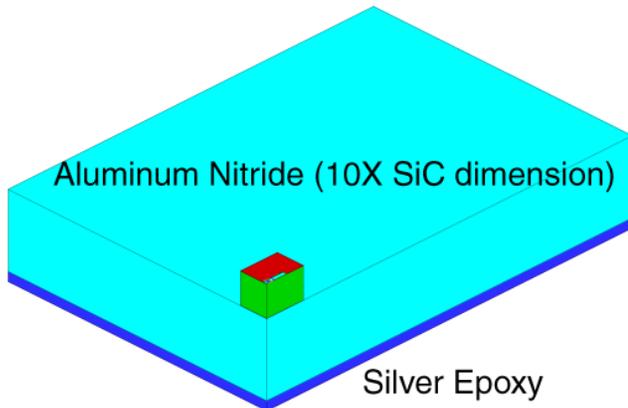
TR module thermal model

**MMIC junction is 54 C
above the module mounting
surface (module rise is 4C)**

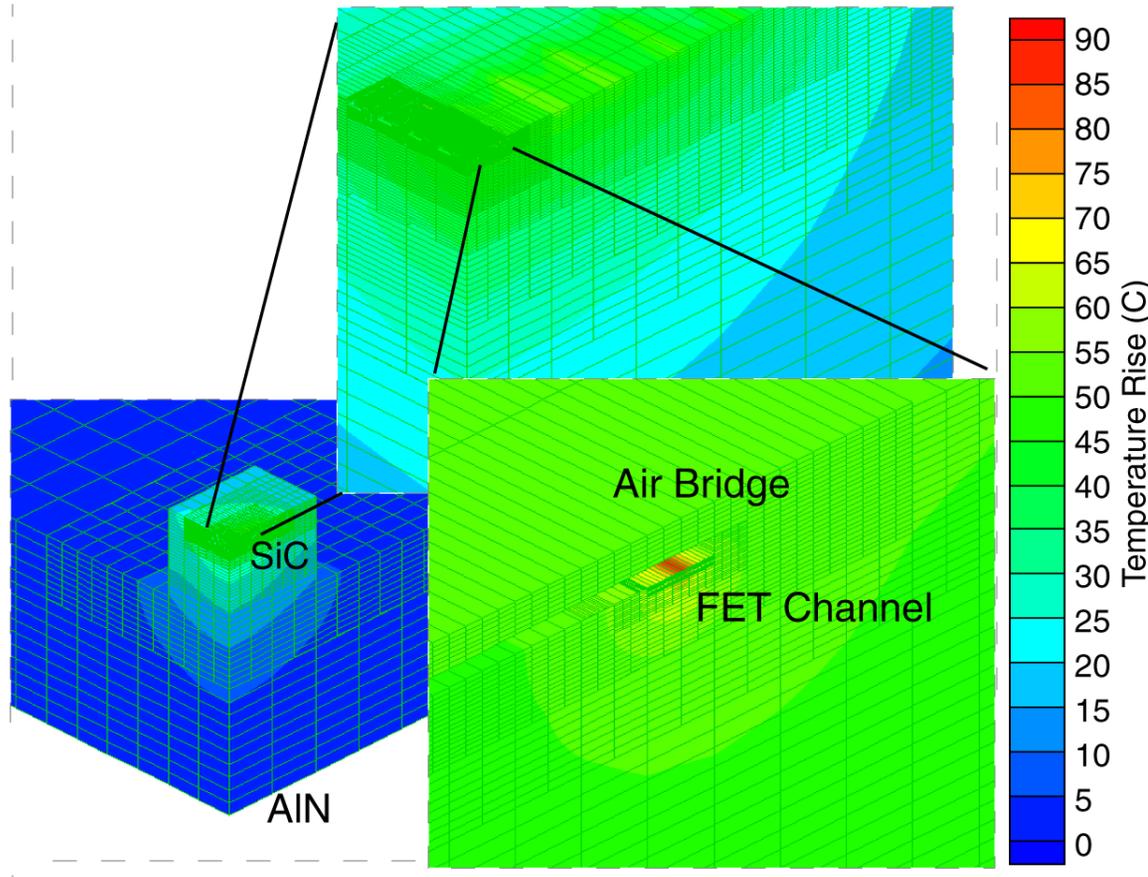
50 C rise from AlSiC pedestal to junction (with CW power dissipation)

Thermal Model of GaN FET

1/4 Section Adaptive Mesh



- **thermosonic die attach (5 μm Au)**
- **4.5 W/mm dissipation**
- **50 μm gate-gate**
- **10 fingers**
- **@125 μm length**

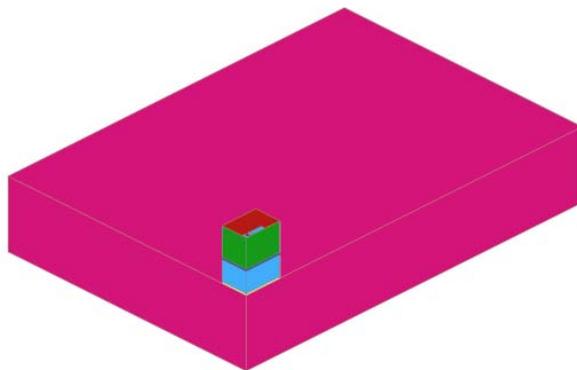


Package Materials /Trades

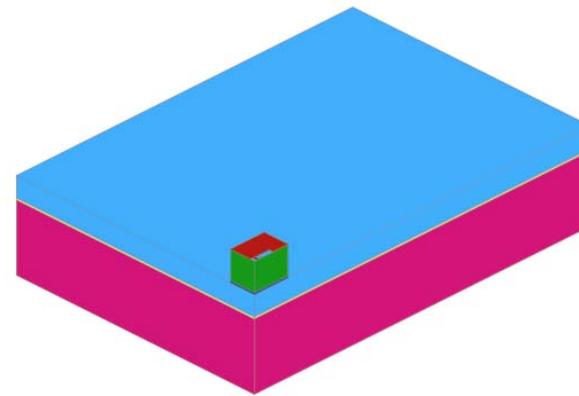
Diamond Heat Spreader

Evaluations at 4.5 W/mm dissipation

	SiC Thk (microns)	Diamond area	Temperature Rise (C)	Comparison case to one AuSn layer and same SiC thickness - no diamond
Thick Discrete	425	same as SiC	91.4	89.3
Thin Discrete	125	same as SiC	84.3	85.0
Thick MMIC	425	same as AlN	80.0	89.3
Thin MMIC	125	same as AlN	72.9	85.0



Diamond heat spreader same size as SiC

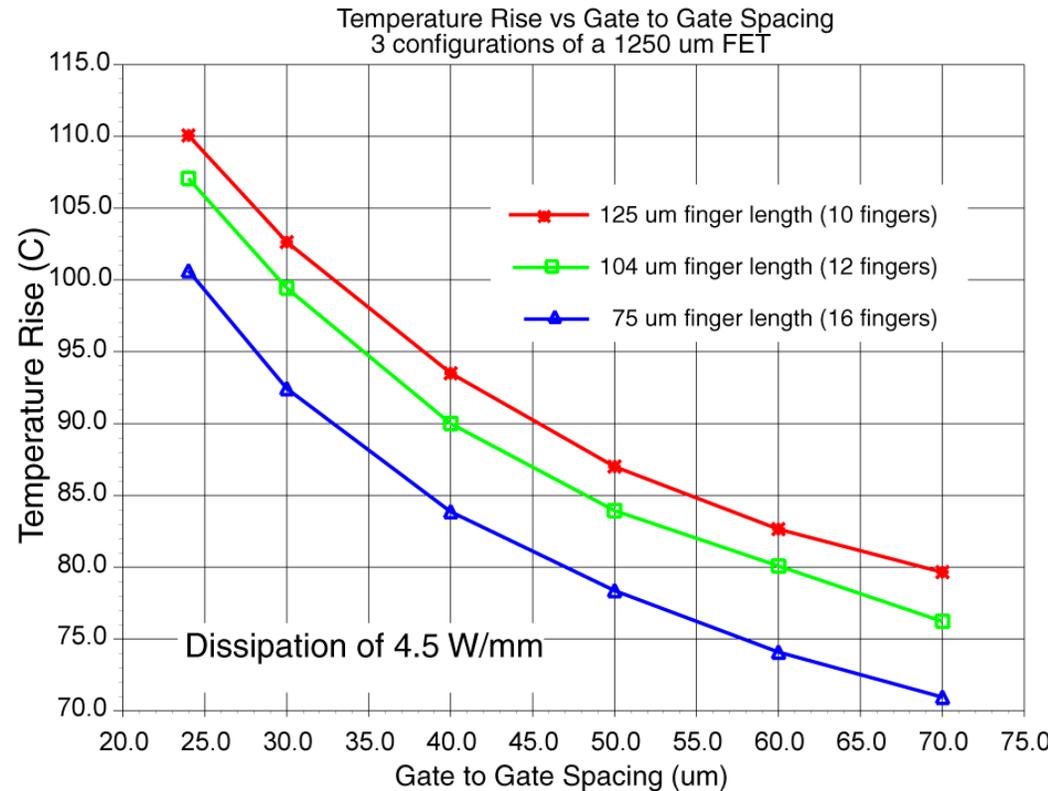
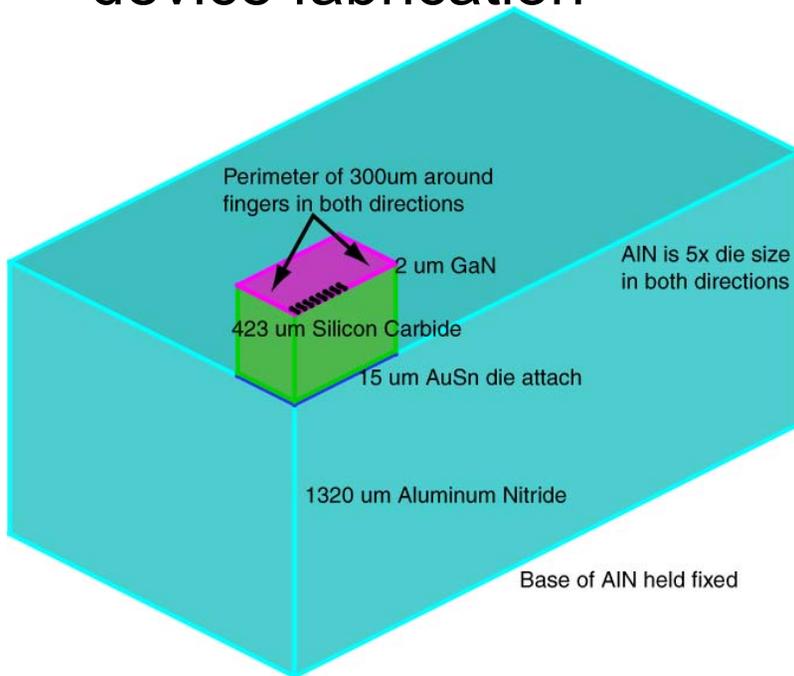


Diamond heat spreader same size as AlN

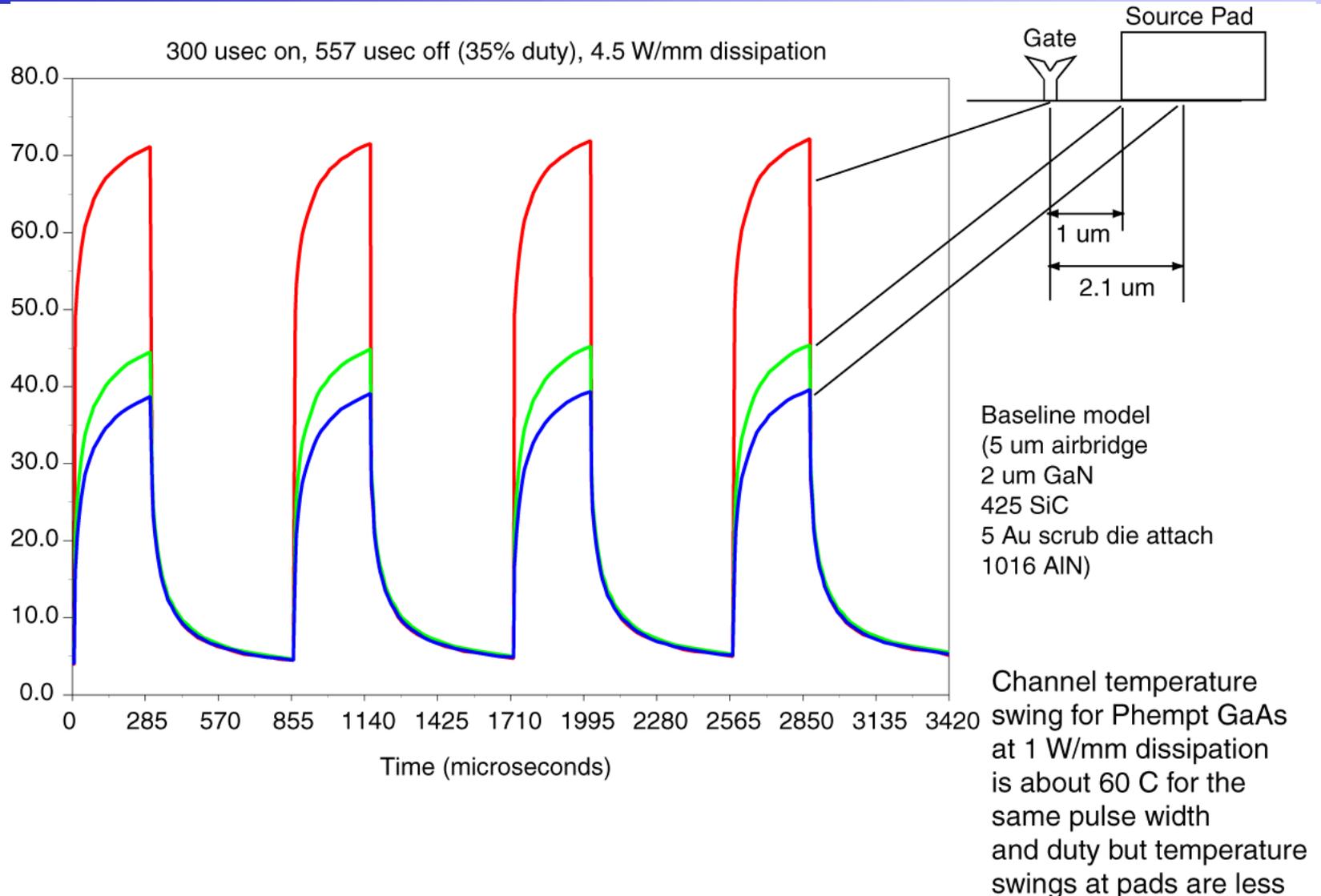
Benefit with diamond for MMICs but not for discrete FETs

GaN FET Channel Spacing Trade

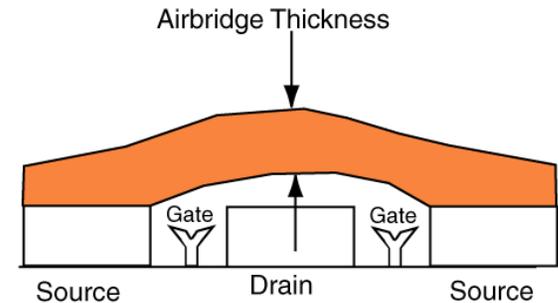
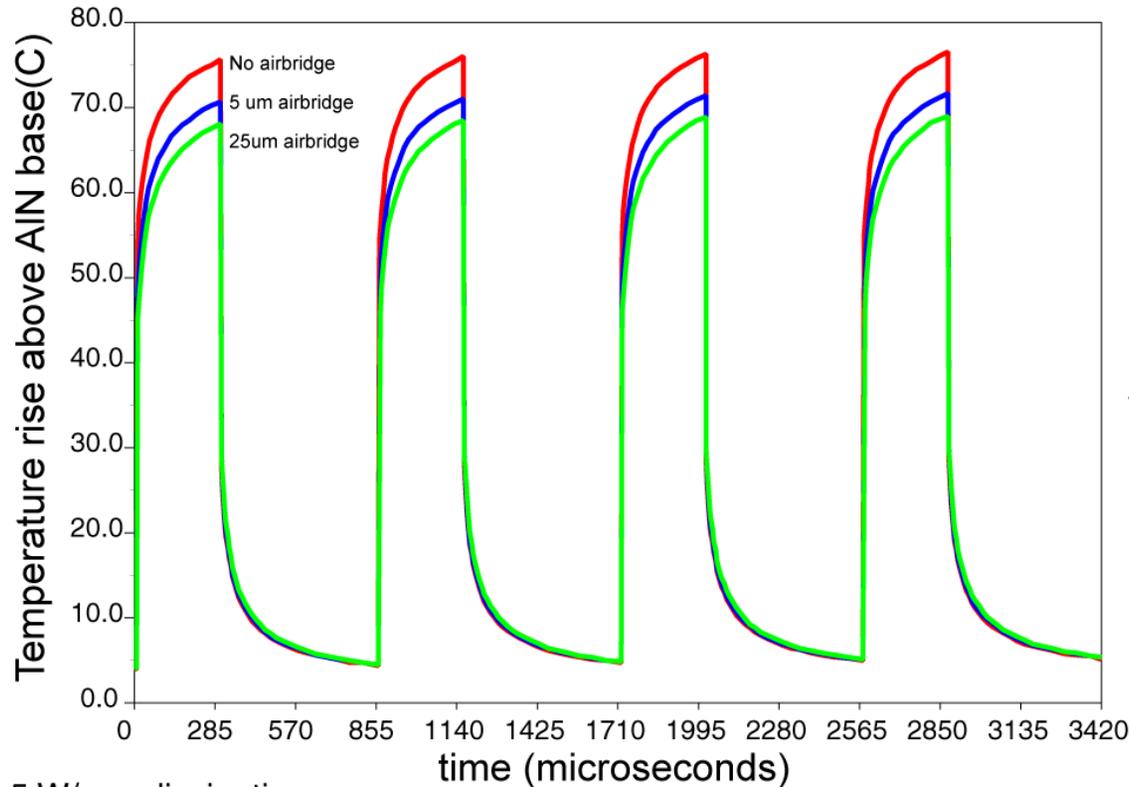
Rapid thermal analysis capability allows design trades prior to device fabrication



Transient Analysis at Pads



Transient Analysis

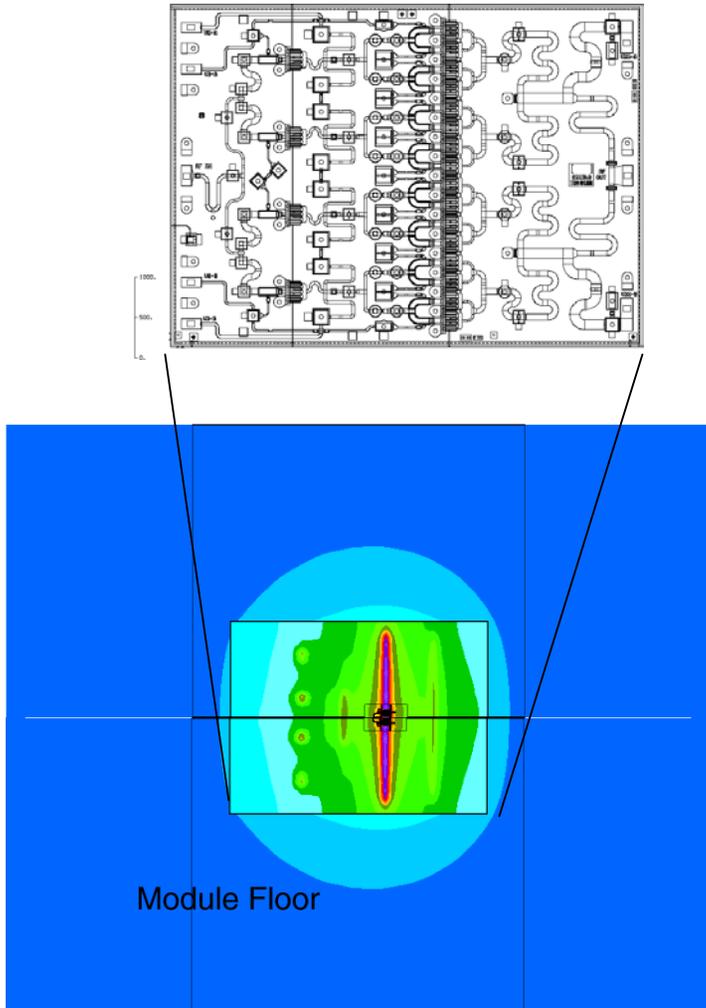


4.5 W/mm dissipation
base of AlN held fixed
SiC conductivity = 272 W/m-K
10 finger FET, 50 um g-g

On for 300 usec, off for 557 usec

2 um GaN
423 um SiC
5 um Au
1016 AlN

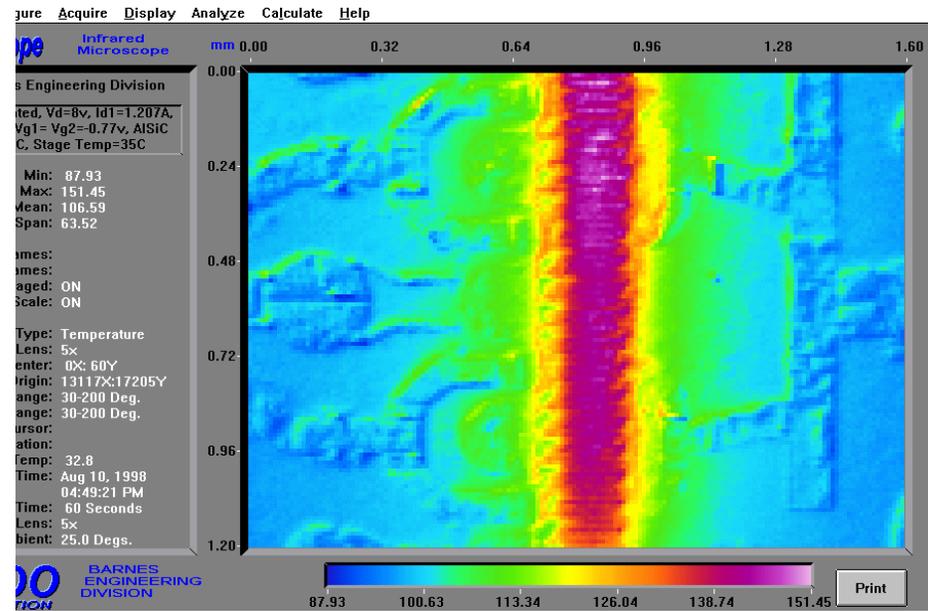
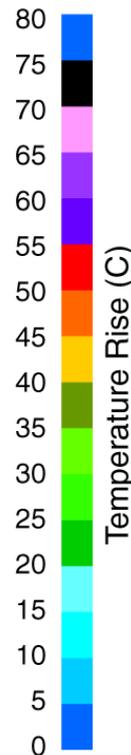
Model Verification with IR



IR at 10 μm resolution

Test: 106 C rise

Model: 102 C rise



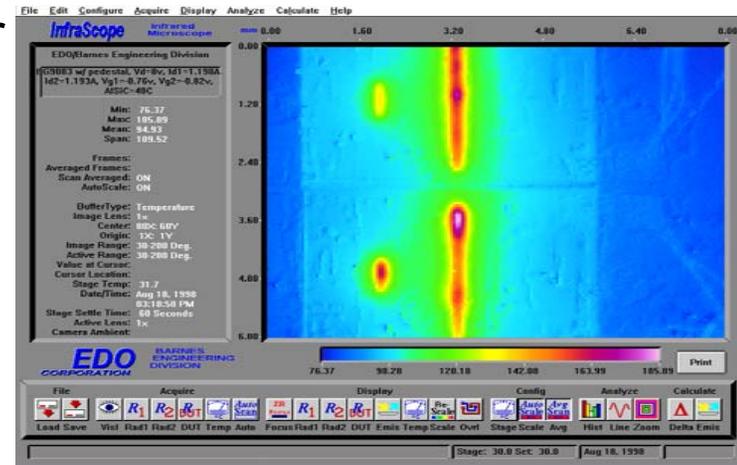
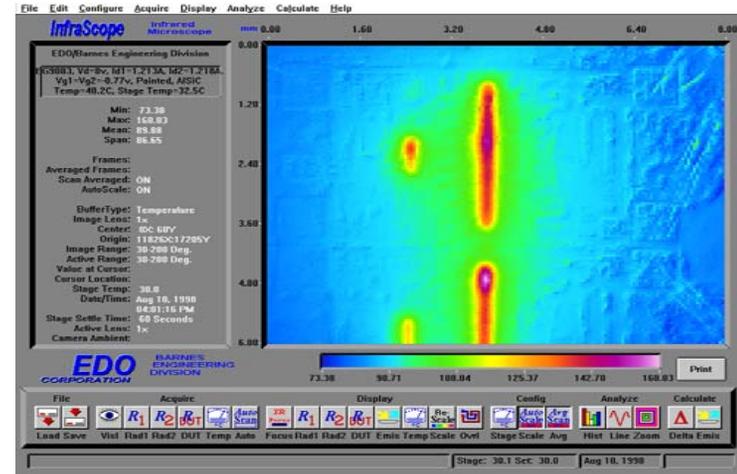
Thermal Interface for Die Attach

Repair and rework concerns favor the use of silver-filled epoxy to attach power amplifiers to module floors - (power amplifier is soldered to a heat spreader which is then attached with epoxy)

Direct Attach

Comparison of direct attach and spreader mounted power amps. Same DC power for both cases, IR images indicate about a 15 - 20 C junction temperature increase for the pedestal mounted part

Heat spreader (10 mil CM15 plus 1 mil epoxy)



- Material interface issues very important
 - Module and die attach (heat flux high)
 - Compliant attach may be required because of CTE concerns
- Thermal analysis needs to be integrated into the power amplifier design process
- Material properties for “thin film” materials at device level are not well known (surface metalization)